

Scanning Probe Microscope

Multimode 8

Principle

Surface analysis. Space-resolved and *in-situ* analysis of sample surfaces in the μm - and nm -area. Measuring principle is based on the interaction of a probe and the sample surface.

Manufacturer	Bruker
Mode	Multimode 8
Imaging Techniques	AFM, STM, EC-STM, SECPM
Environmental Conditions	Air, liquid
Temperature	Room temperature
Max. Scan Sector	10 x 10 μm^2
Max. Vertical Area	2.5 μm
Optional Equipment	Bi-potentiostat for <i>in-situ</i> measurement in liquids
